







From single superconducting components to integrated qubit circuits:

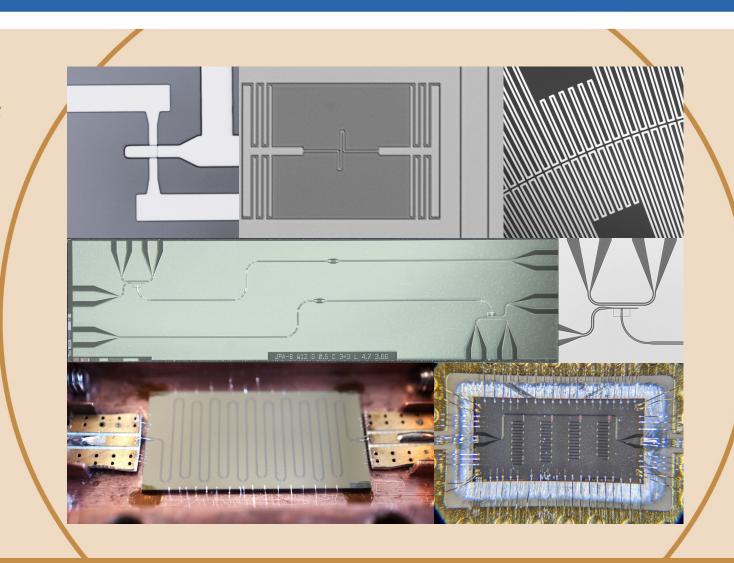
Vertical **Josephson junctions**, low-loss **superconducting resonators** and **high-kinetic inductance** films

Felix Klaus Ahrens

Fondazione Bruno Kessler (Trento)
Centre for Sensors and Devices

fahrens@fbk.eu www.fbk.eu



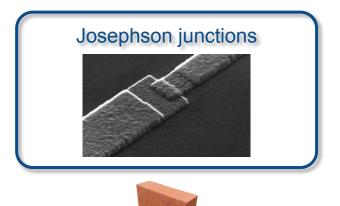


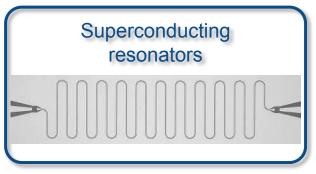


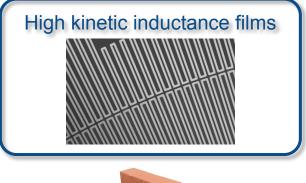














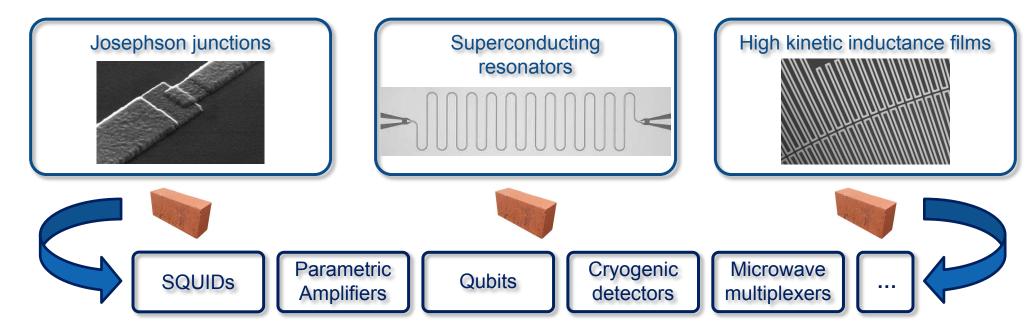










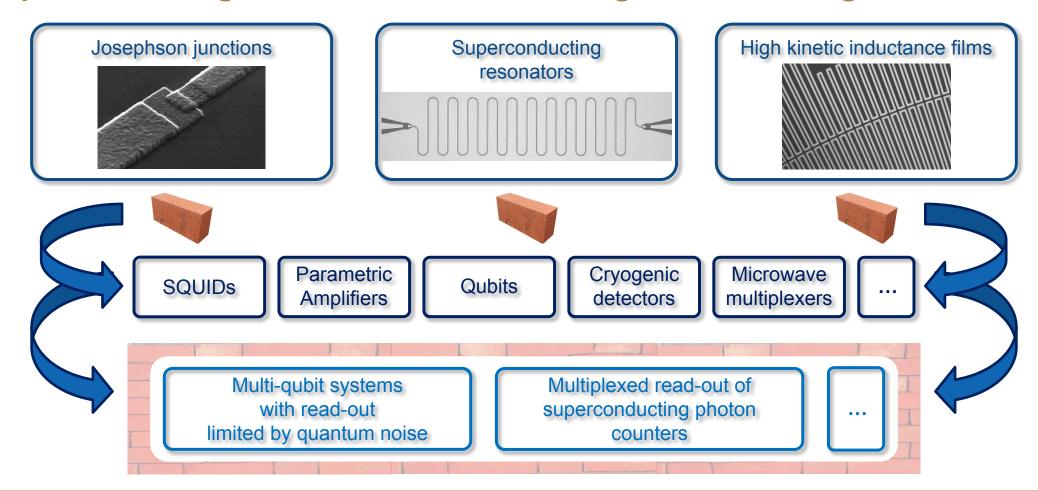










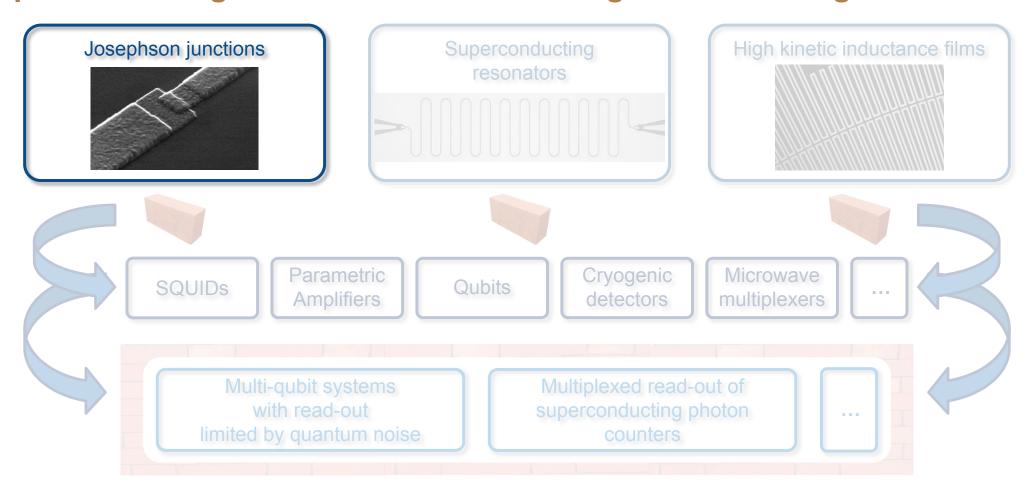












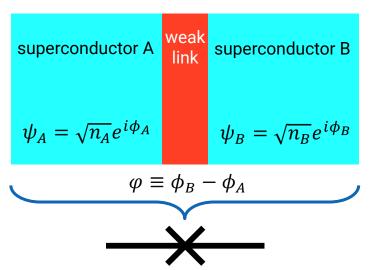








Josephson junctions





Brian Josephson

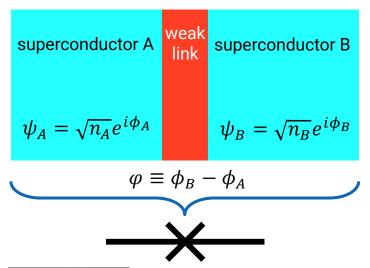








Josephson junctions

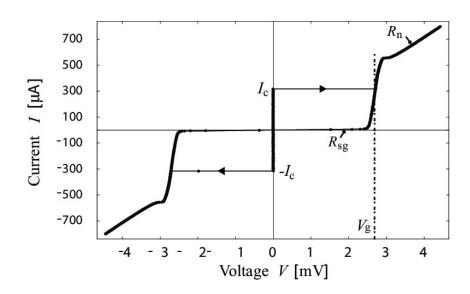




Brian Josephson

Josephson equations

$$I(t) = I_C \sin(\varphi(t))$$
$$\frac{\partial \varphi}{\partial t} = \frac{2e V(t)}{2}$$



$$V = \frac{\Phi_0}{2\pi \cdot I_c \cdot \cos\varphi} \cdot \frac{dI}{dt} = L_J(\varphi) \cdot \frac{dI}{dt}$$

→ non-linear and tunable inductance









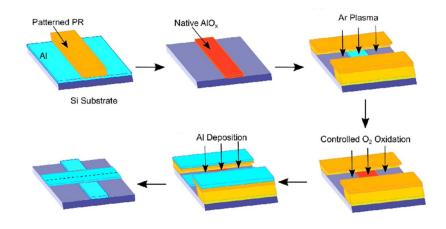
Cross Josephson junctions at FBK







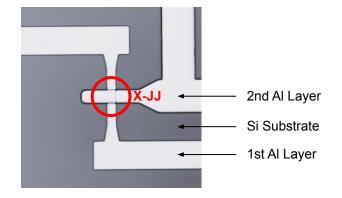






Advantages

- High control on areas (and on junction parameters)
- Two-layers process





Challenge

- Develop an efficient Ar plasma cleaning
- Optimise the second lithographic step (lift-off)









Cross Josephson junctions at FBK - 1st generation



Quantum Science and Technology in Trento



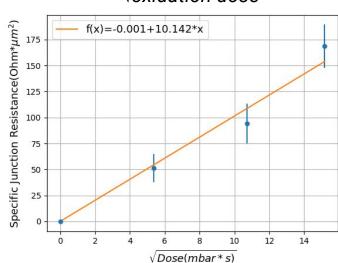




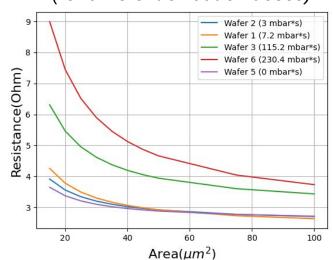
The junction normal resistance $R_{\rm N}$ is related to the critical current $I_{\rm c}$: $I_{\rm c}R_{\rm N}=(\pi/4)\cdot V_{\rm g}$

Resistance measurements at T = 300 K

Junction resistance vs √oxidation dose

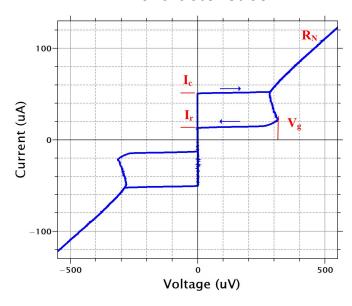


Junction resistance vs junction area (for different oxidation doses)



Cryo measurements at T = 20 mK

IV characteristics











Cross Josephson junctions at FBK - 2nd generation



Quantum Science and Technology in Trent





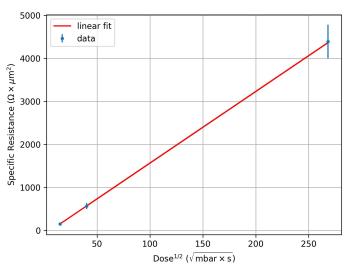


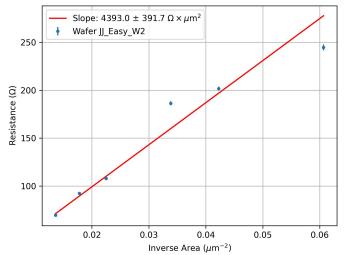
The junction normal resistance $R_{\rm N}$ is related to the critical current $I_{\rm c}$: $I_{\rm c}R_{\rm N}=(\pi/4)\cdot V_{\rm g}$

Resistance measurements at T = 300 K

Junction resistance vs junction area

Junction resistance vs √oxidation dose







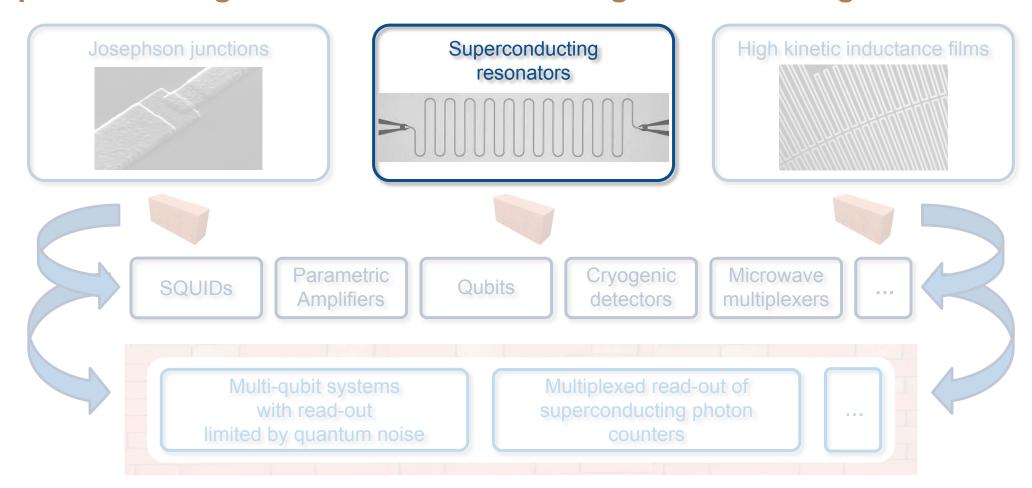
Cryo measurements at T = 20 mK











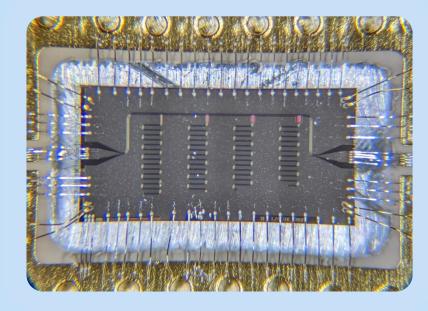


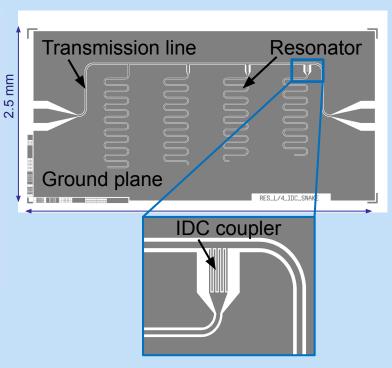


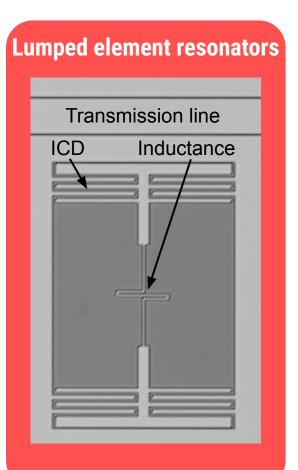




CPW quarter-wave resonators







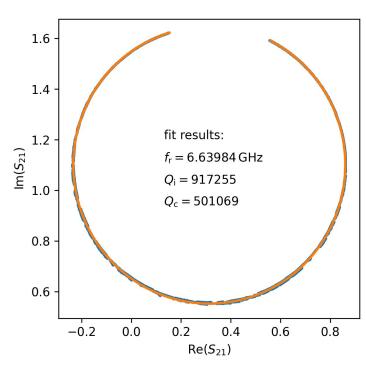




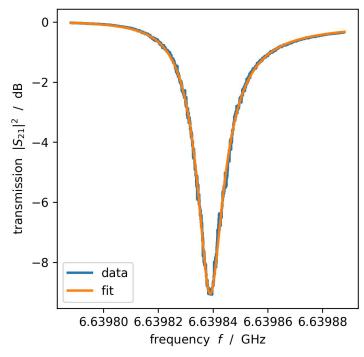




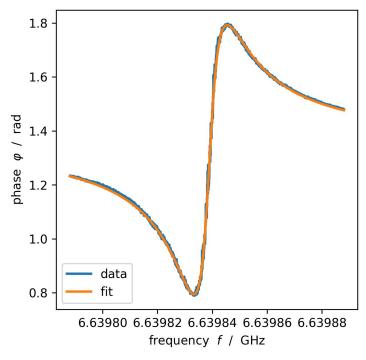
Most recent results with aluminium based lumped element resonators



Fit in complex S_{21} plane



Transmission $|S_{21}|^2$



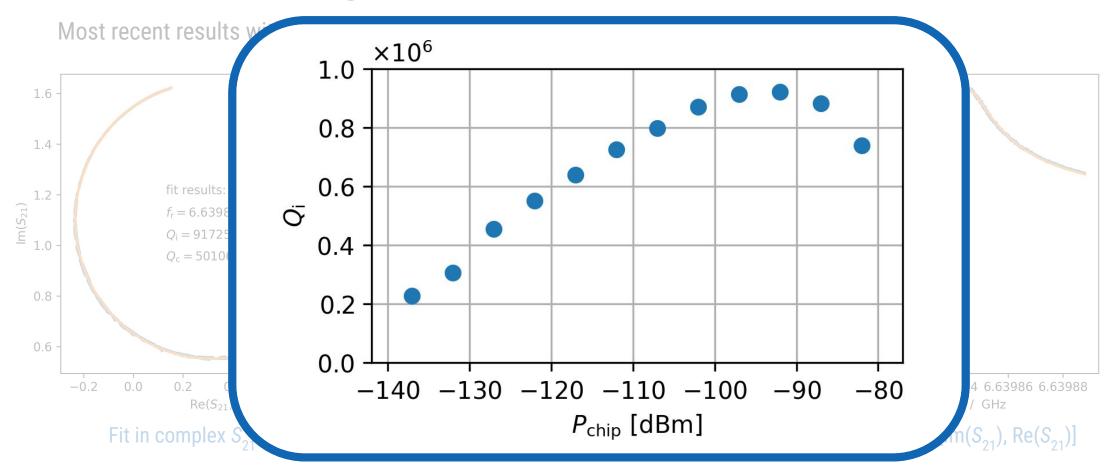
Phase $arctan2[Im(S_{21}), Re(S_{21})]$









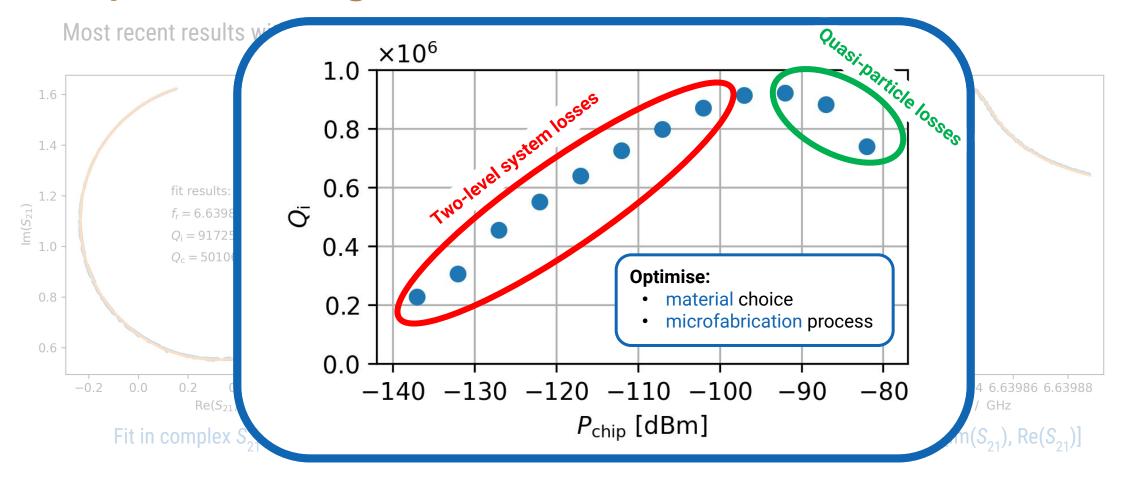










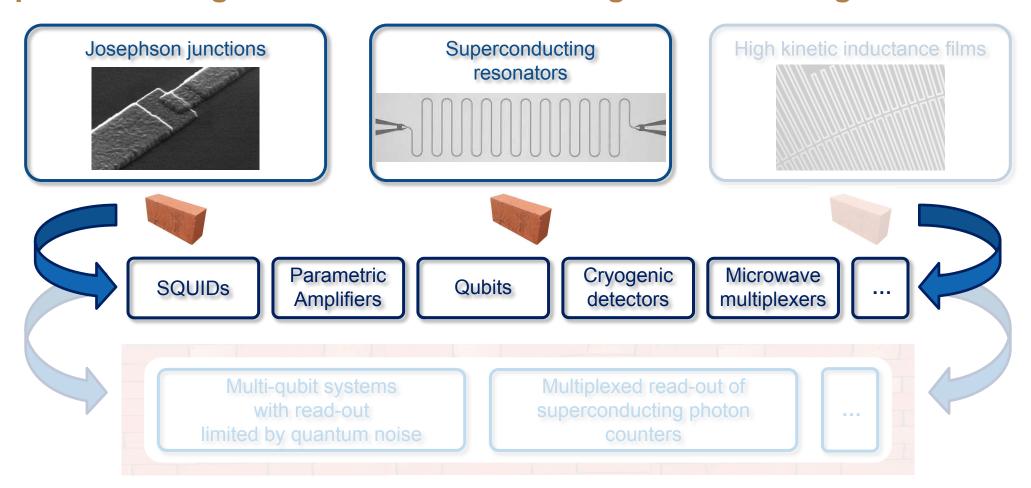
















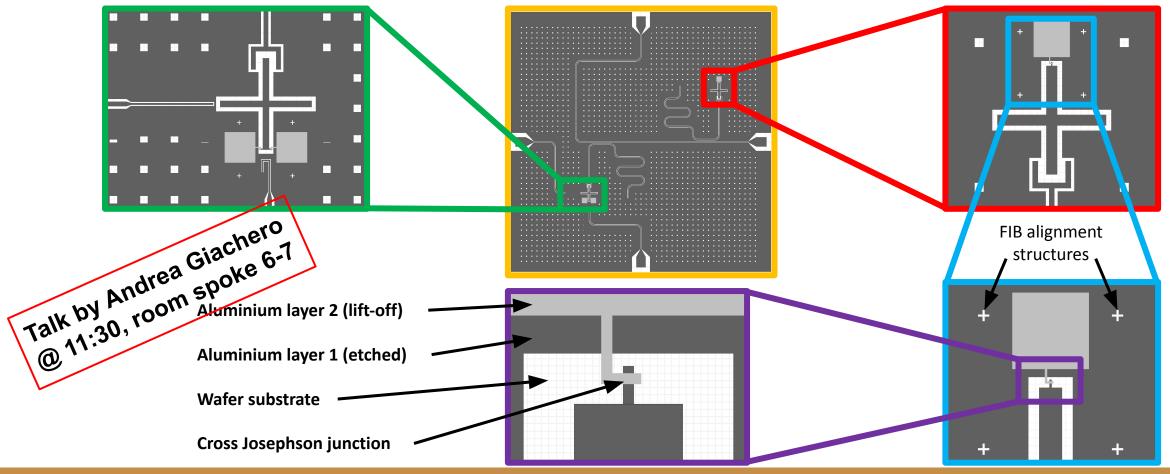




Microfabrication of qubits





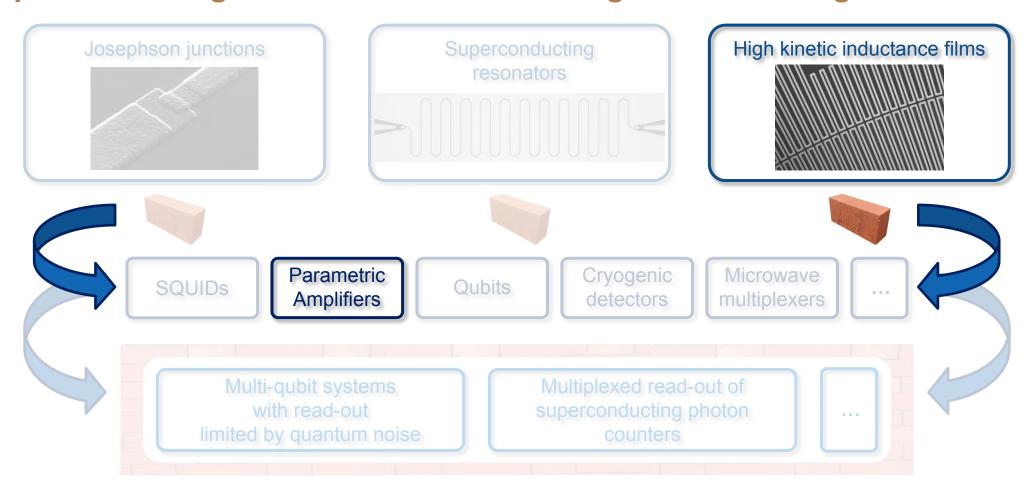










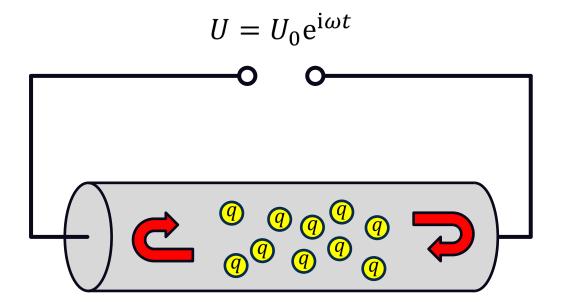








High kinetic inductance films



$$\sigma = \frac{nq^2\tau}{m(1+i\omega\tau)}$$
 Kinetic inductance:
- large collision time τ

- high frequency ω

Superconductor:

$$au o \infty$$
, $m = 2m_e$, $q = 2e$

Cooper pair density n = n(I)

$$\Rightarrow L(I) \approx L_0 \cdot \left(1 + \frac{I^2}{I_*^2}\right)$$

$$L_0 = \frac{R_S \hbar}{\pi \Lambda} \qquad I_* \propto 1/\sqrt{R_n}$$







High kinetic inductance films

Interesting materials:high-resistivity superconductors

- Our choice: NbTiN
 - \rightarrow high resistivity (~100-200 m Ω cm)
 - → high critical temperature (~12-13 K)

Superconductor:

$$\tau \to \infty$$
, $m = 2m_e$, $q = 2e$

Cooper pair density n = n(I)

$$\Rightarrow L(I) \approx L_0 \cdot \left(1 + \frac{I^2}{I_*^2}\right)$$

$$L_0 = \frac{R_S \hbar}{\pi \Lambda} \qquad I_* \propto 1/\sqrt{R_n}$$









Optimisation of NbTiN thin films: parameter exploration

Sputter system:PVD Kenosistec 800 C

Sputter target:



Fabrication run $R1$				
Wafer	P/W	p/mbar	$f_{ m Ar}/{ m sccm}$	$f_{\rm N_2}/{\rm sccm}$
T1	700	2e-3	50	5
T2	700	3e-3	50	4
T3	700	3e-3	50	5
T4	700	3e-3	50	6
T5	1200	3e-3	50	5
T6	700	3e-3	50	7
T7	700	3e-3	50	8
T8	700	3e-3	50	6.5
T9*	700	3e-3	50	7
T10	600	3e-3	50	7

 $[*]T = 300 \,^{\circ}\text{C}$



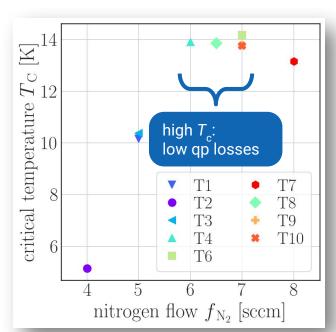




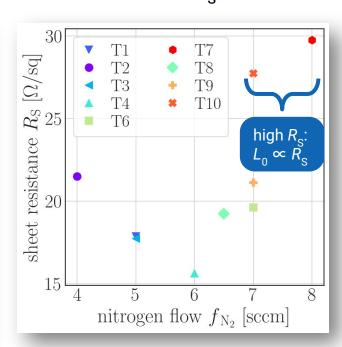


Optimisation of NbTiN thin films: parameter exploration

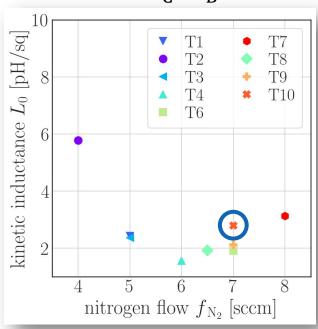
Measured T_c :



Measured R_s :



$$L_0 = \frac{R_{\rm S} \cdot \hbar}{\pi \cdot T_{\rm C} \cdot k_{\rm B} \cdot 1.762}$$



 \rightarrow Recipe T10: high T_c and sufficiently high R_s

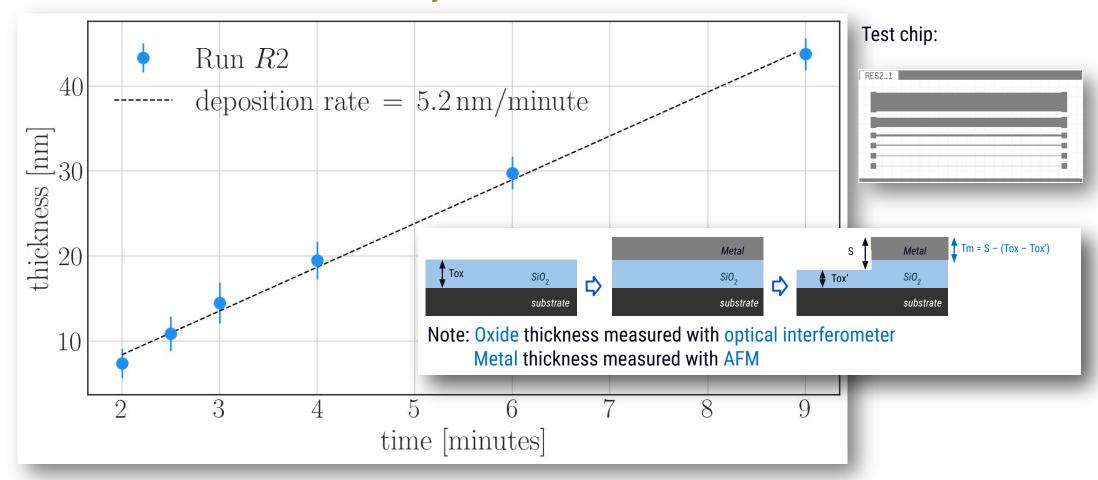








Calibration of NbTiN deposition rate





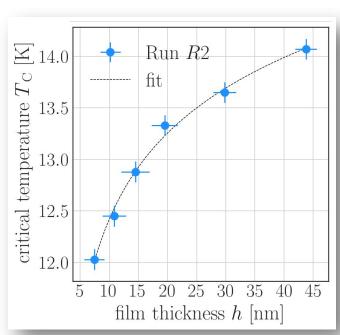




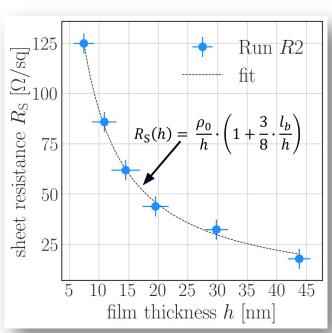


Calibrate film thickness h vs kinetic inductance L_0

Measured T_c :

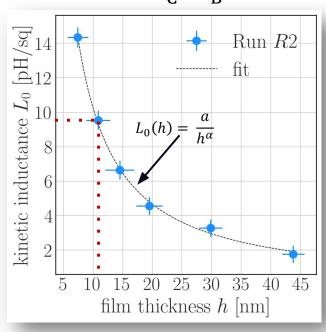


Measured R_s :



Fuchs' model (doi: 10.1017/S0305004100019952)

 $L_0 = \frac{R_{\rm S} \cdot \hbar}{\pi \cdot T_{\rm C} \cdot k_{\rm B} \cdot 1.762}$



Phenomenological model

 \rightarrow Use film thickness h as L_0 tuning parameter





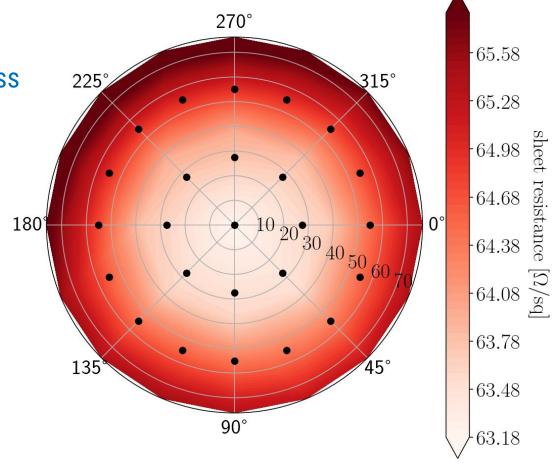




Uniformity on wafer scale

Estimation of the uniformity of the film thickness

- → Measurement of the sheet resistance (25 points over the 6 " wafer)
- \rightarrow Variation is about 4%
- → Radial gradient (thinner film at the edge)





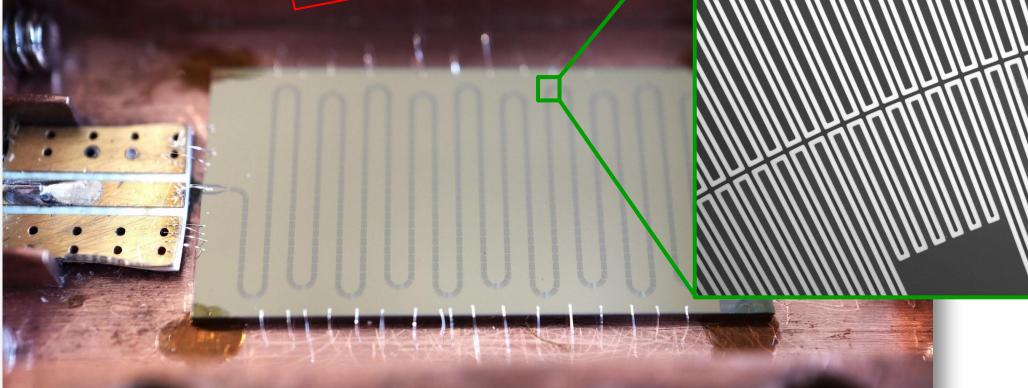






KI-TWPAs

Talk by Federica Mantegazzini @ 9:45, room spoke 6-7







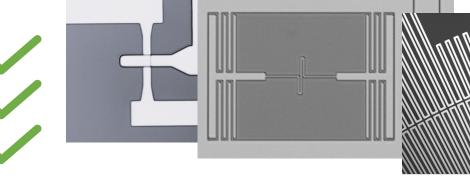




Conclusion

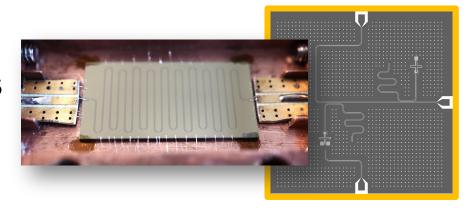
Building blocks ready:

- Josephson junctions
- Microwave resonators
- High kinetic inductance films



Currently ongoing:

- Further improvement of building blocks
- Integrating building blocks into circuits









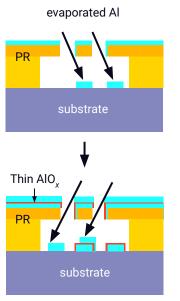


How to microfabricate Josephson junctions

Dolan technique

(aka shadow evaporation)

Al/AlOx/Al

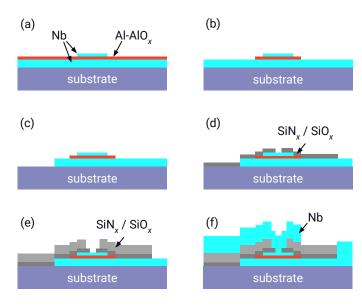


Cord B. et al (2006) 10.1116/1.2375090

Cross junctions Al/AlOx/Al (c) (a) Si Substrate (e) Controlled O2 Oxidation Ar Plasma O2 Ashing of PMMA PR\LOR (h) Al Deposition

Bal M. et al (2021) 10.1063/5.0048621

Window-type / Trilayer Nb/Al-AlO₂/Nb



Kempf S. et al (2013) 10.1088/0953-2048/26/6/065012